

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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*	B	US-7,221,043	05-2007	Silverbrook, Kia	257/676
*	C	US-7,215,377	05-2007	Hoshino et al.	348/452
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